

Surface Structure, Interface Morphology, and RITD performance in the 6.1 Å Compound Semiconductors

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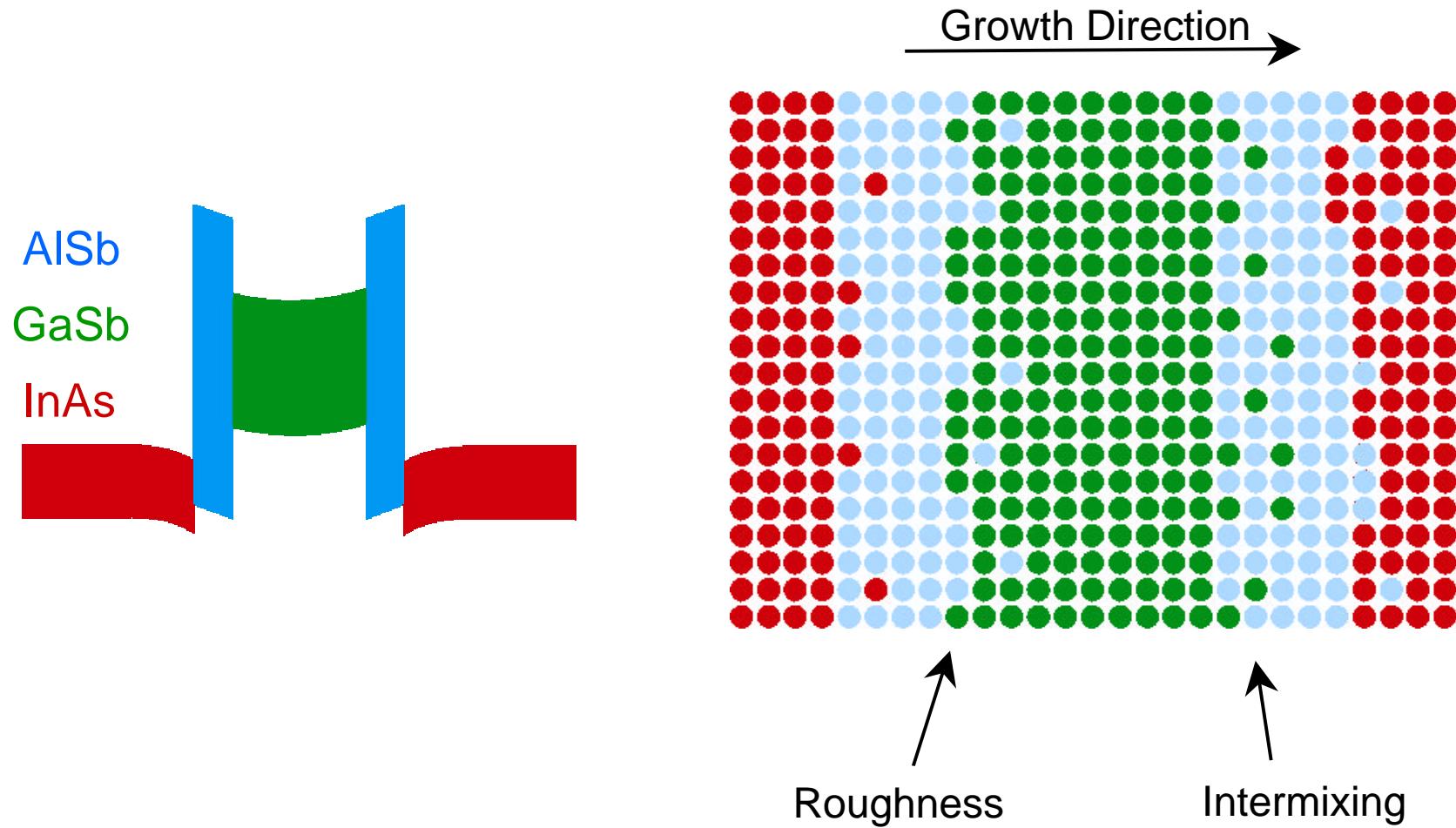


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Washington, DC*

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and Applications of 6.1 Å III-V Semiconductors
31 July - 2 Aug 2001

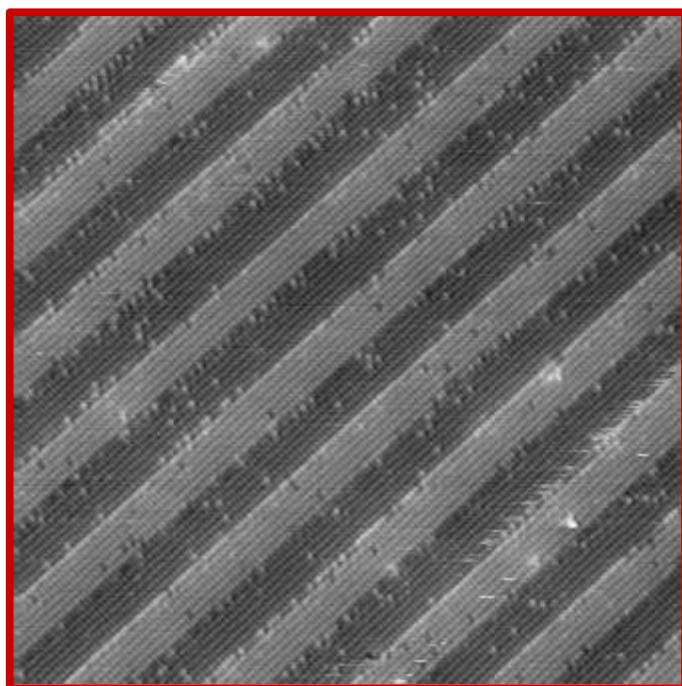
High “Interface to Volume Ratio”



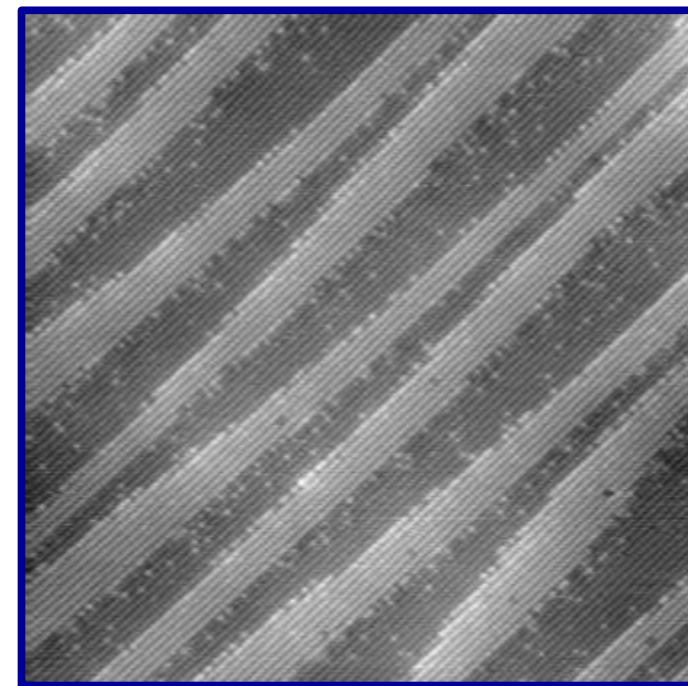
The importance of growth parameters

GaSb / InAs superlattice

10 nm



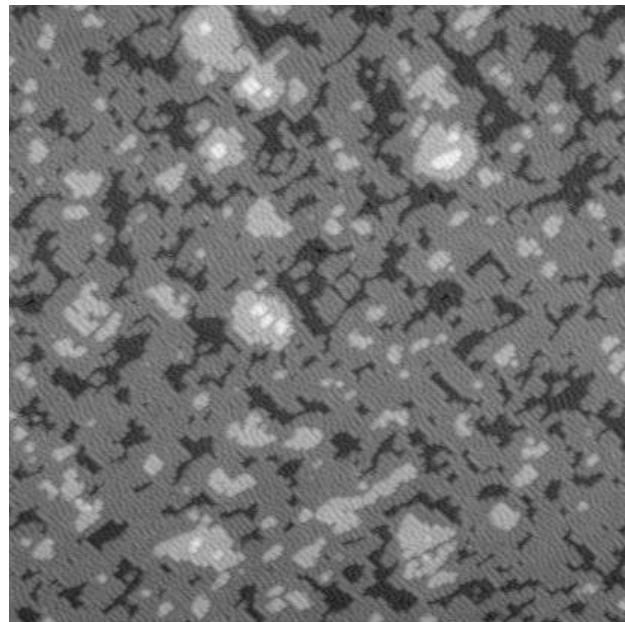
grown with **As₂**



grown with **As₄**

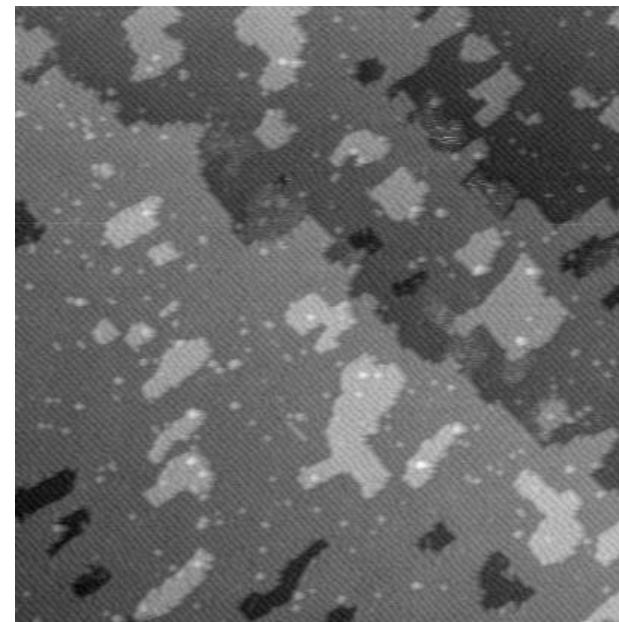
Lower AlSb barrier in RITD-like structure at two growth temperatures

20 nm



400 °C

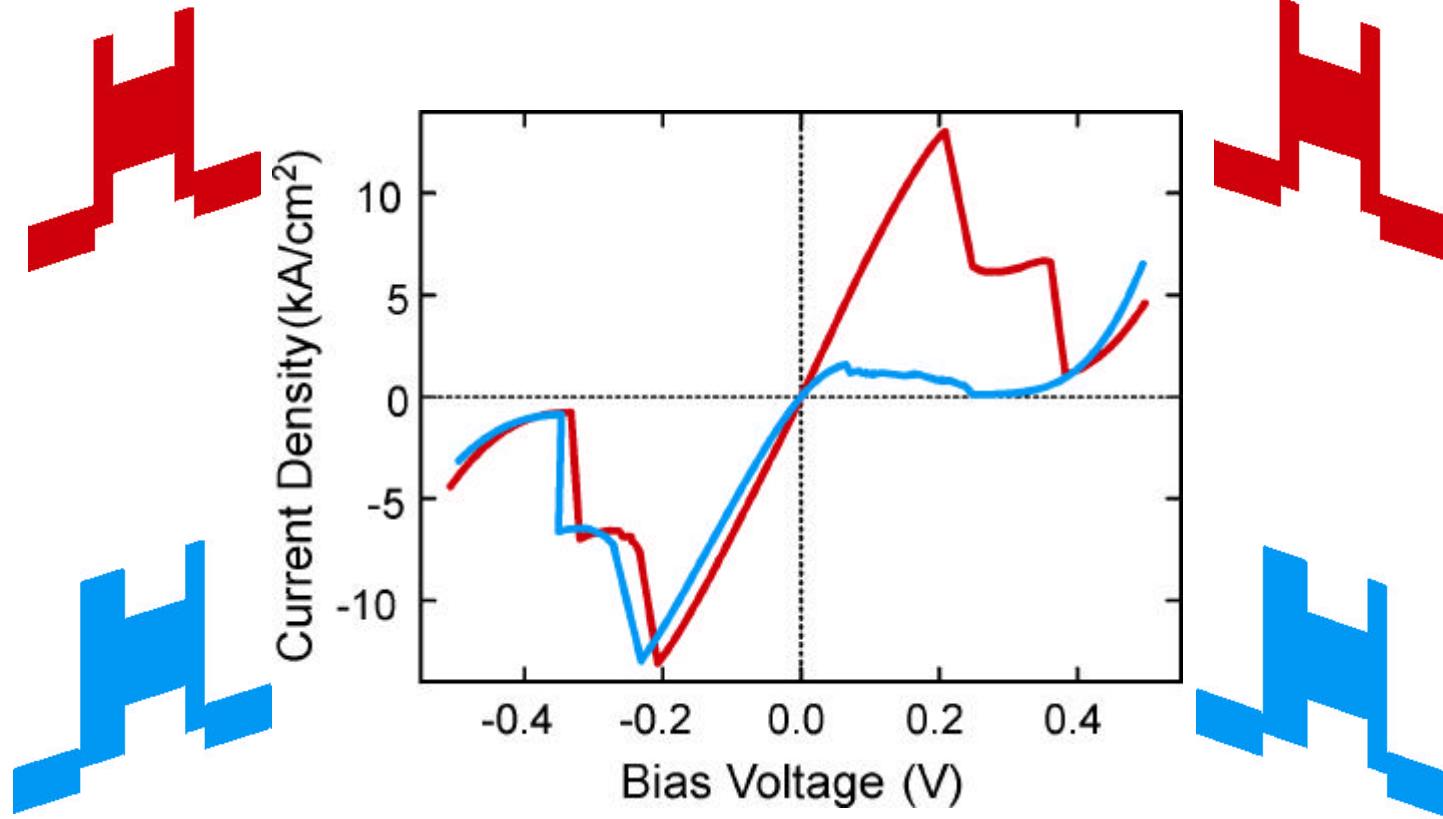
20 % lower monolayer



470 °C

5 % lower monolayer

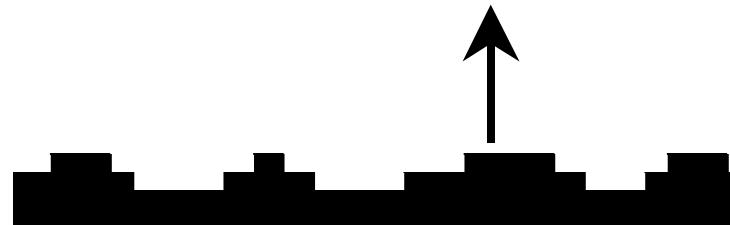
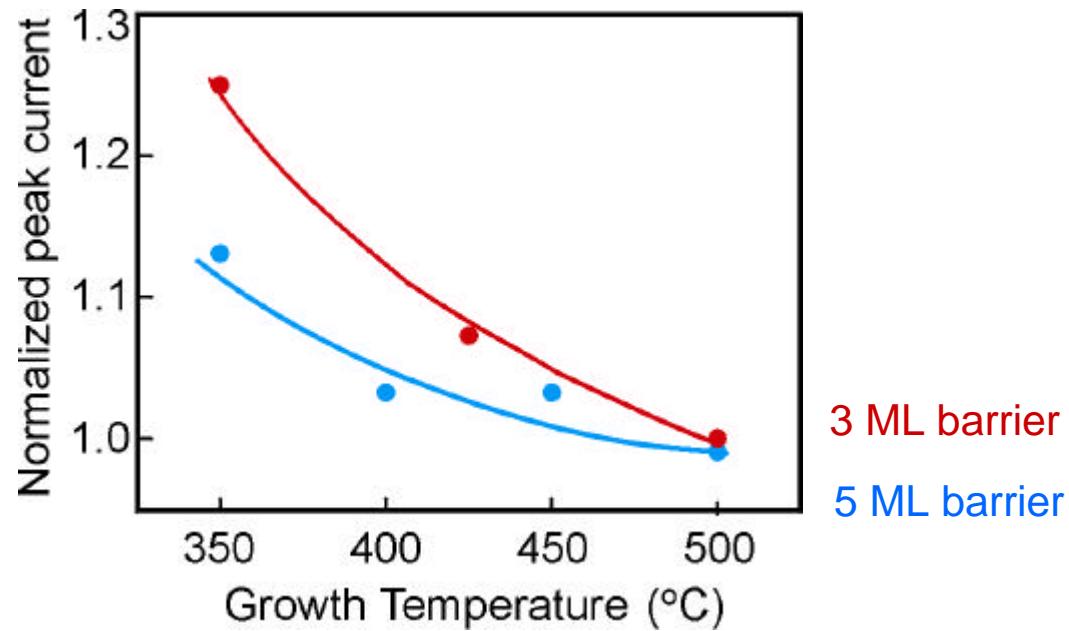
Forward bias I-V peak is sensitive to bottom barrier



Simplifies interpretation of interface effects

Influence of Roughness on Peak Current

Forward bias: bottom barrier

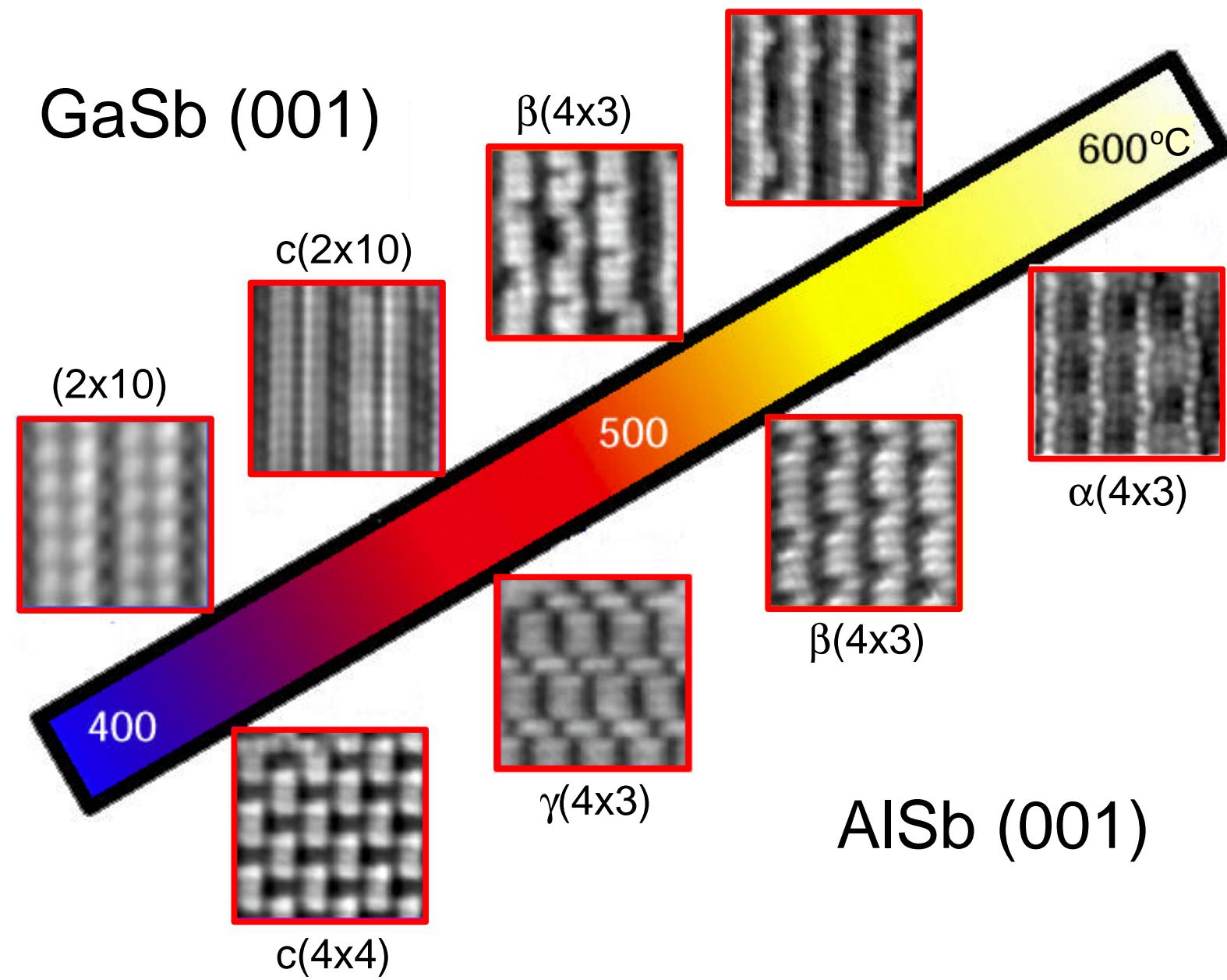


Rough barrier: same volume,
smaller effective thickness



Ideal barrier

GaSb (001)



AlSb (001)

Al

“Stoichiometry-induced roughness”

Sb



surface
✓



surface
✓

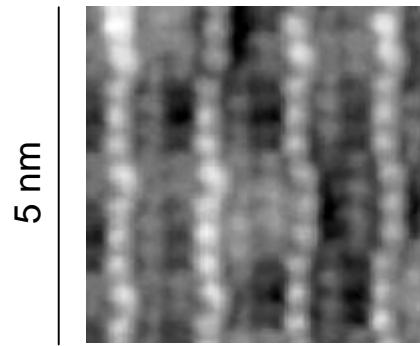


surf ✓ - Sb → surf ✓ + islands

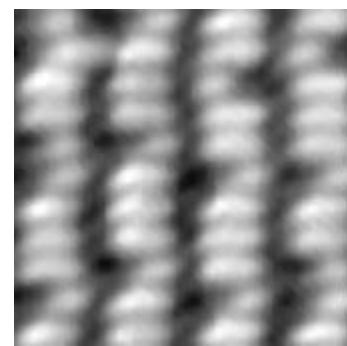
Al
Sb

AlSb surface structures

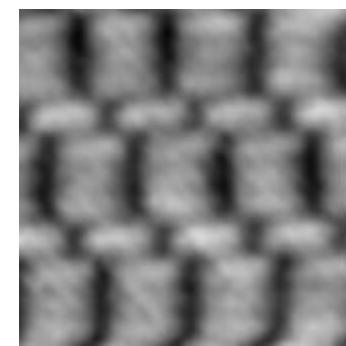
$\alpha(4\times3)$



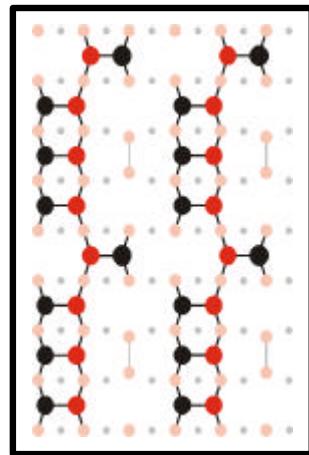
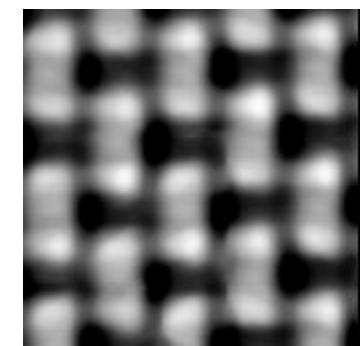
$\beta(4\times3)$



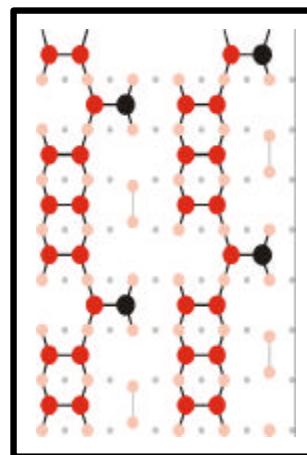
$\gamma(4\times3)$



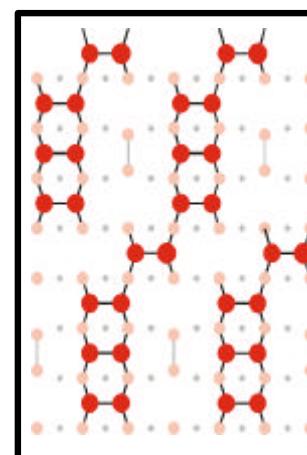
$c(4\times4)$



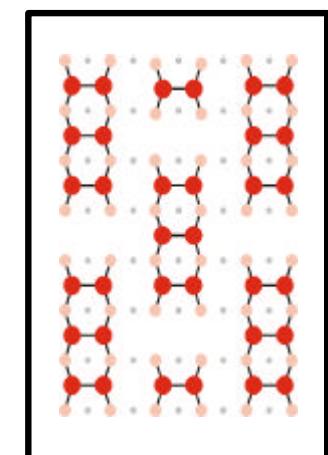
1/3 ML Al
1 1/3 ML Sb



1/12 ML Al
1 7/12 ML Sb

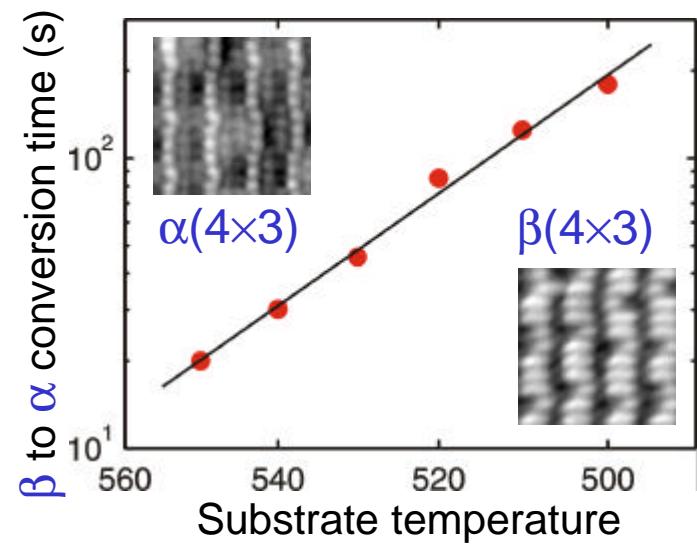
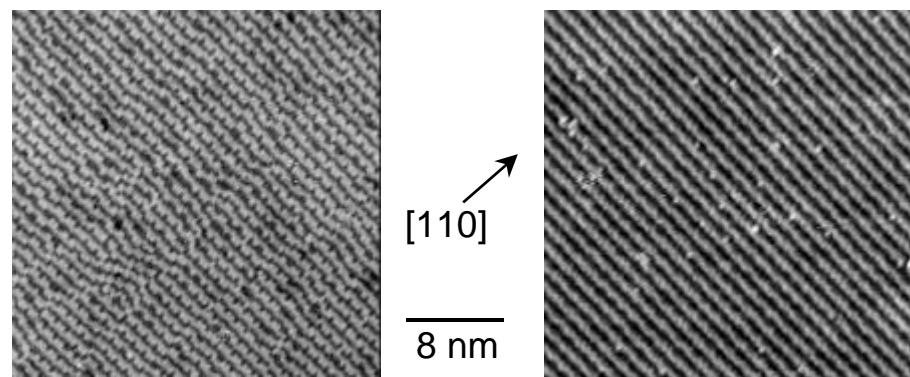
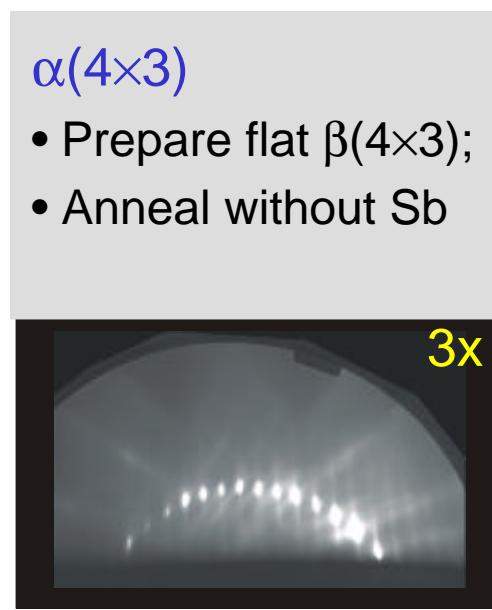
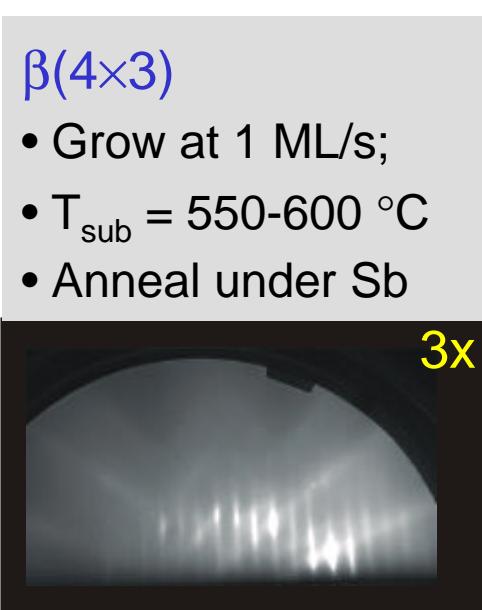


1 2/3 ML Sb

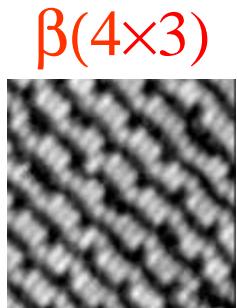


1 3/4 ML Sb

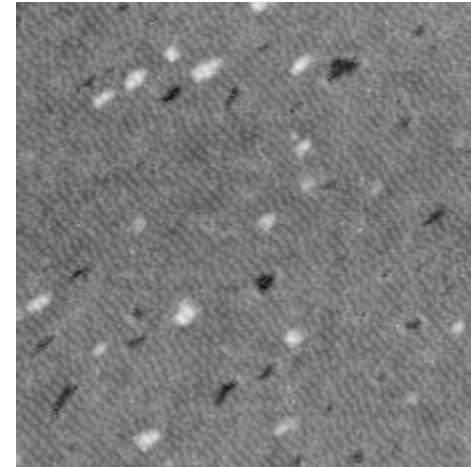
Preparation of flat $\beta(4\times3)$ and $\alpha(4\times3)$ surfaces



Add 1 ML AlSb to flat $\beta(4\times3)$ and $\alpha(4\times3)$ surfaces

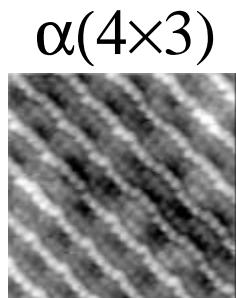


1 ML AlSb

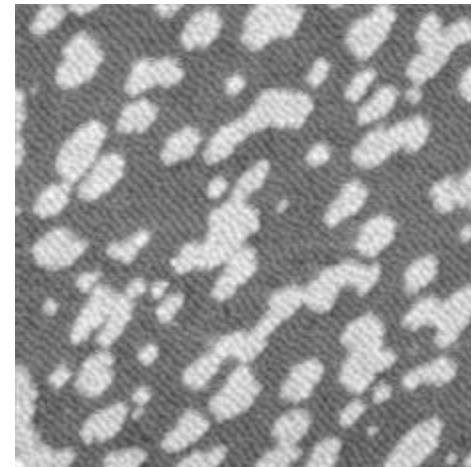


Growing surface
is $\beta(4\times3)$

20 nm [110]



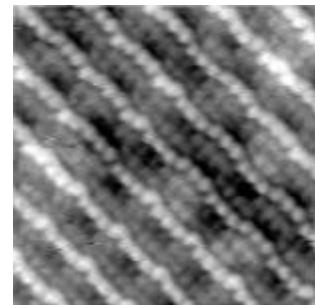
1 ML AlSb



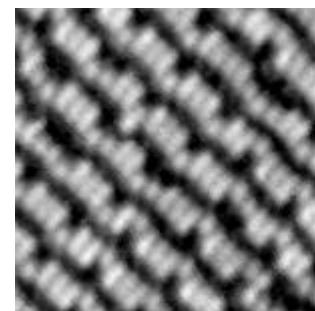
Islands form due to extra aluminum in $\alpha(4\times3)$

Phase shift of RHEED oscillations

$\alpha(4\times3)$

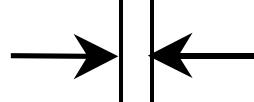


β surface exists under typical
(Sb-rich) growth conditions



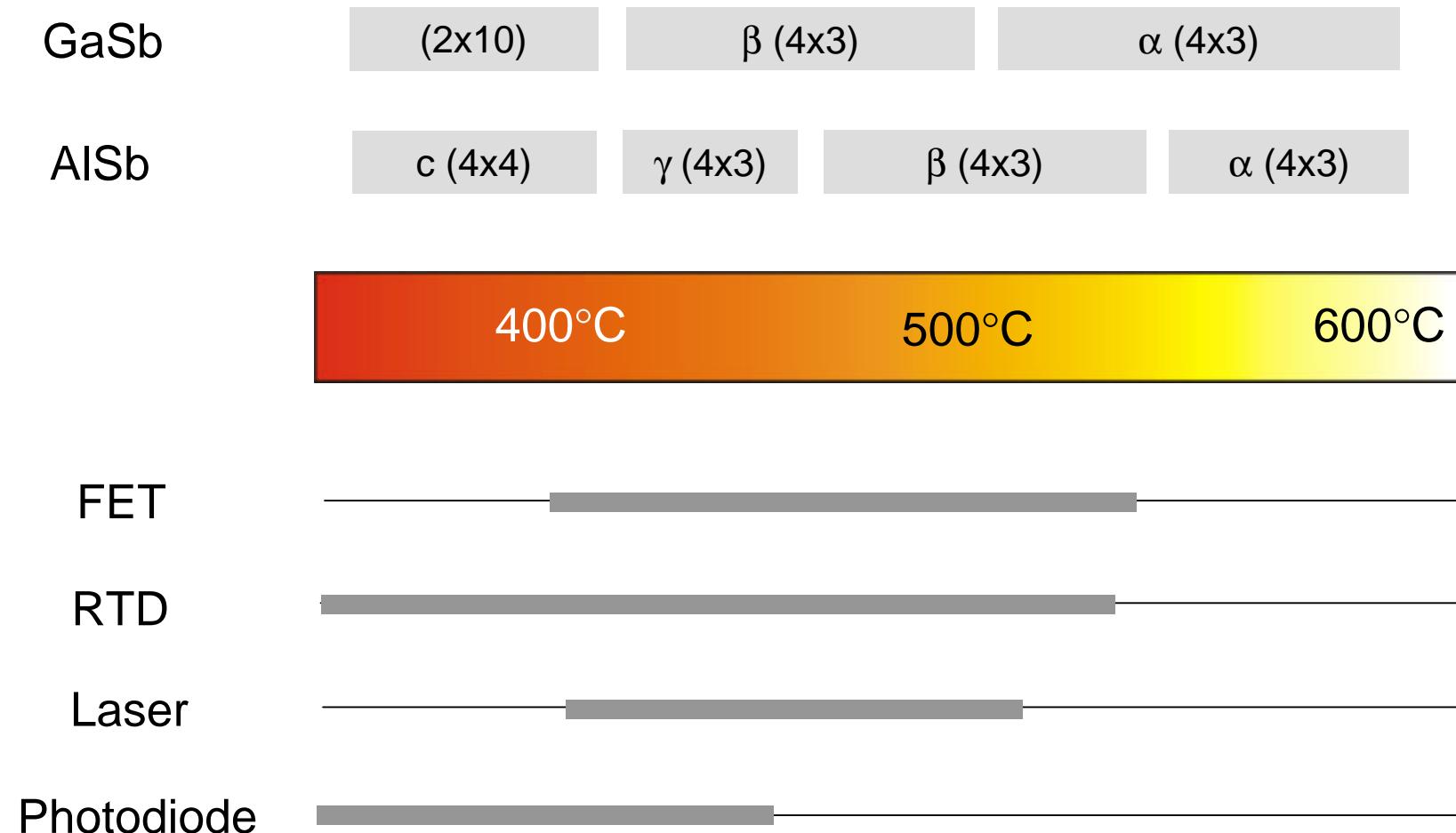
$\beta(4\times3)$

Phase shift
 $\sim 1/4$ ML

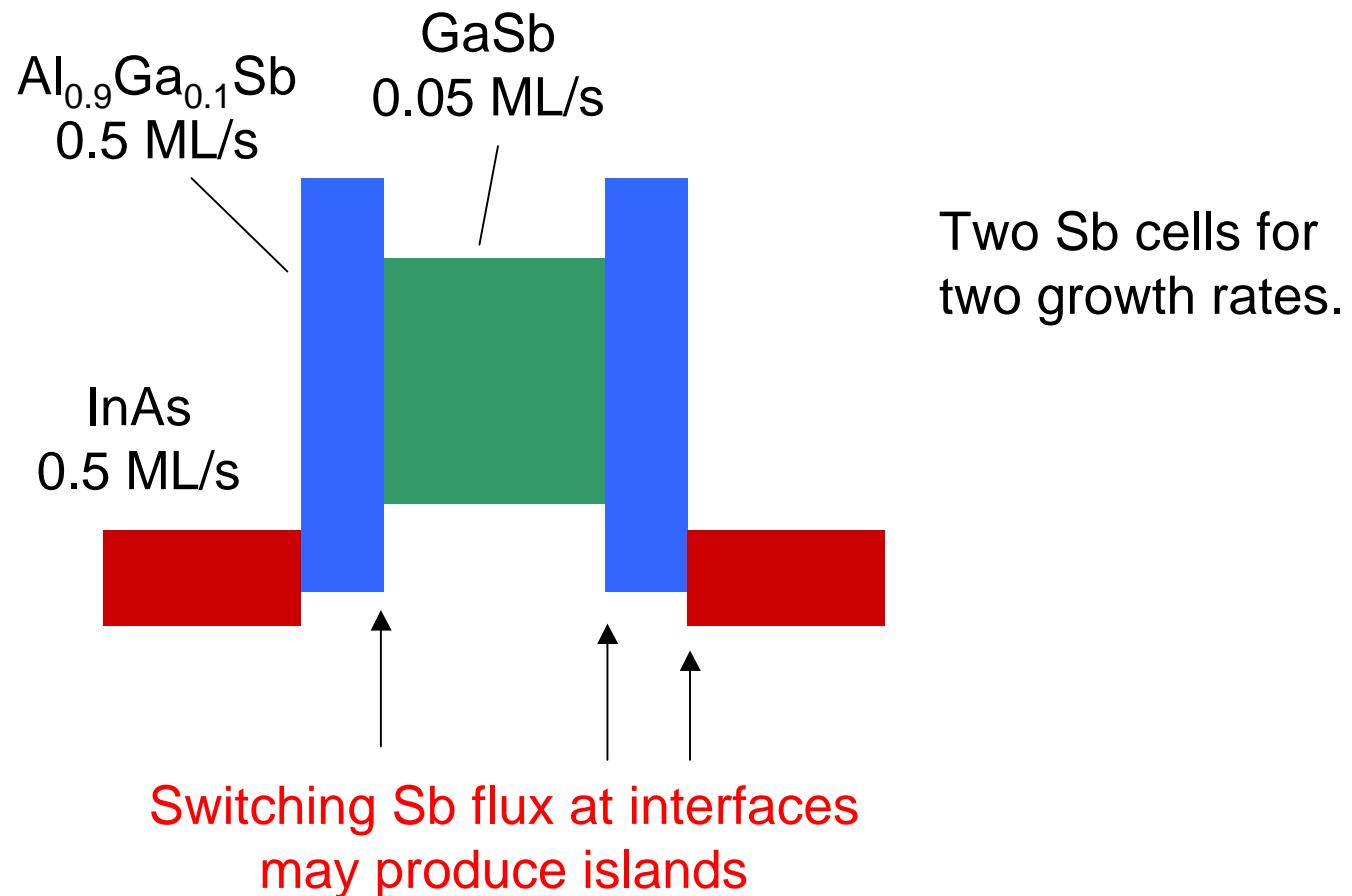


$1/4$ ML extra aluminum in $\alpha(4\times3)$ gives head start in oscillations

Device growths and surface reconstructions

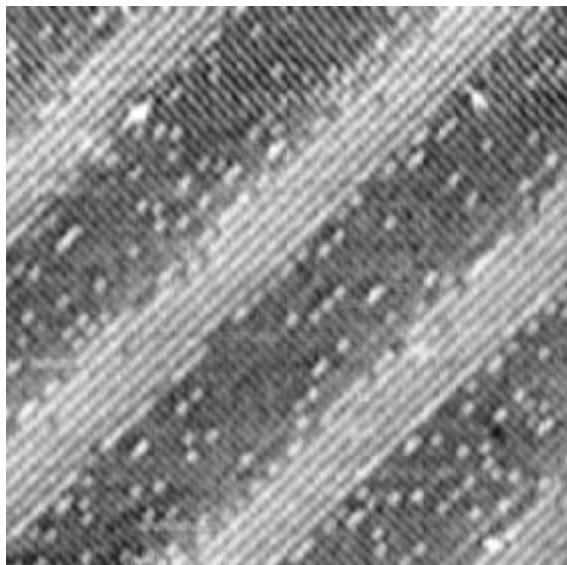


A growth scenario: RITD with alloy barriers



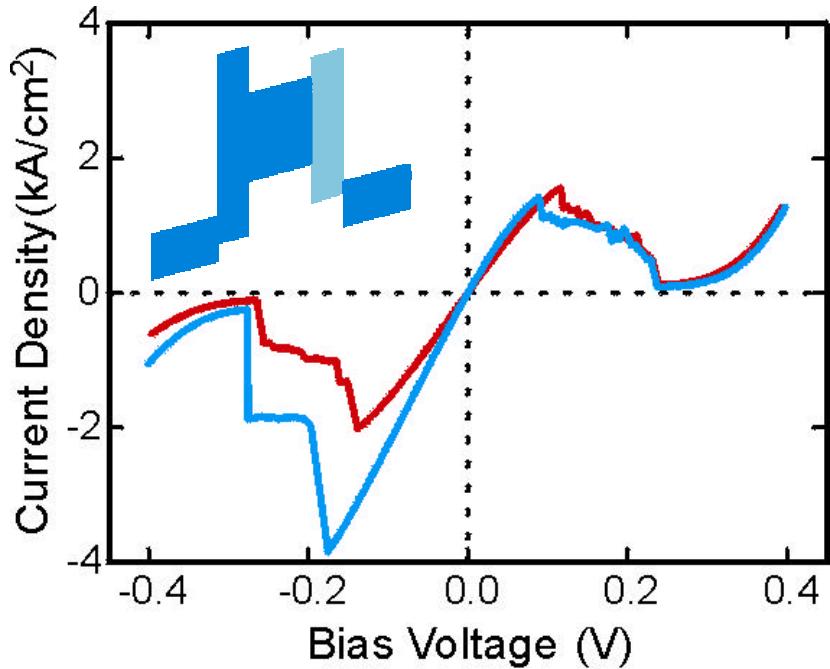
AlGaSb Alloy barriers

GaSb / AlGaSb superlattice

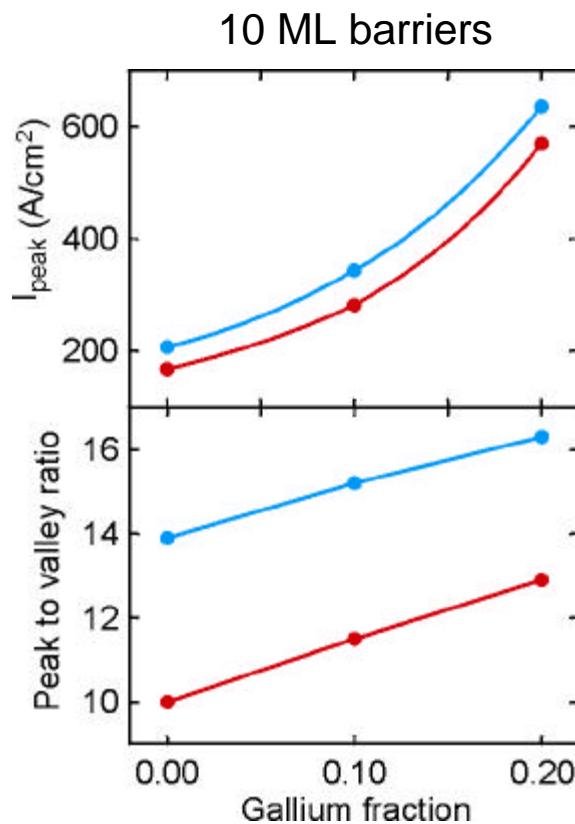
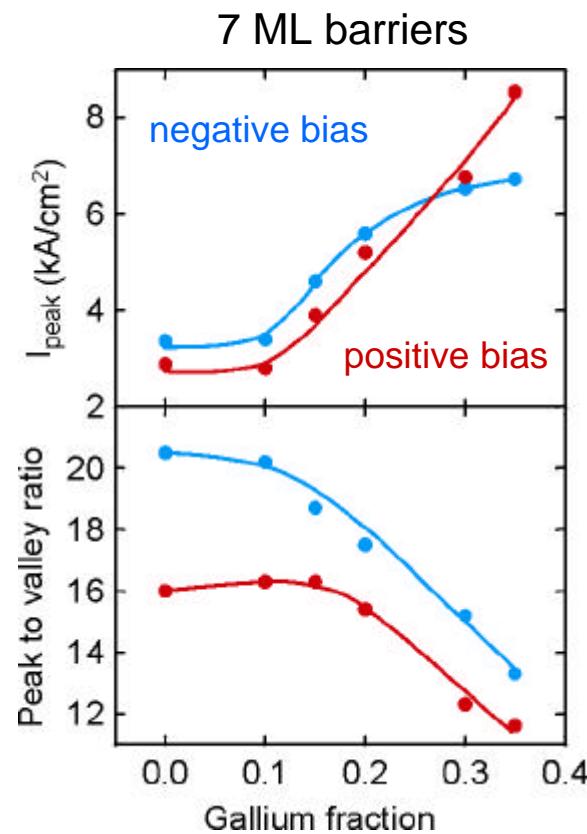


GaSb $\text{Al}_{0.95}\text{Ga}_{0.05}\text{Sb}$

Symmetric (both barriers AlSb)
Asymmetric (top barr. $\text{Al}_{0.7}\text{Ga}_{0.3}\text{Sb}$)



Performance Advantages of AlGaSb barriers

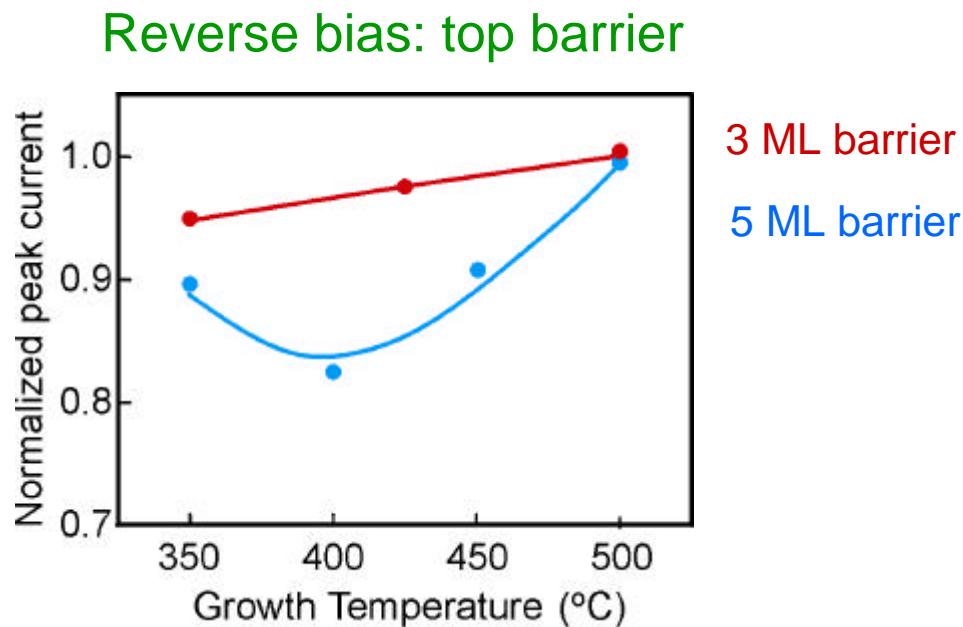


2-3 times boost
in peak current

P/V suffers
little if at all

Opportunity for high currents with thicker barriers
that are less sensitive to interface effects.

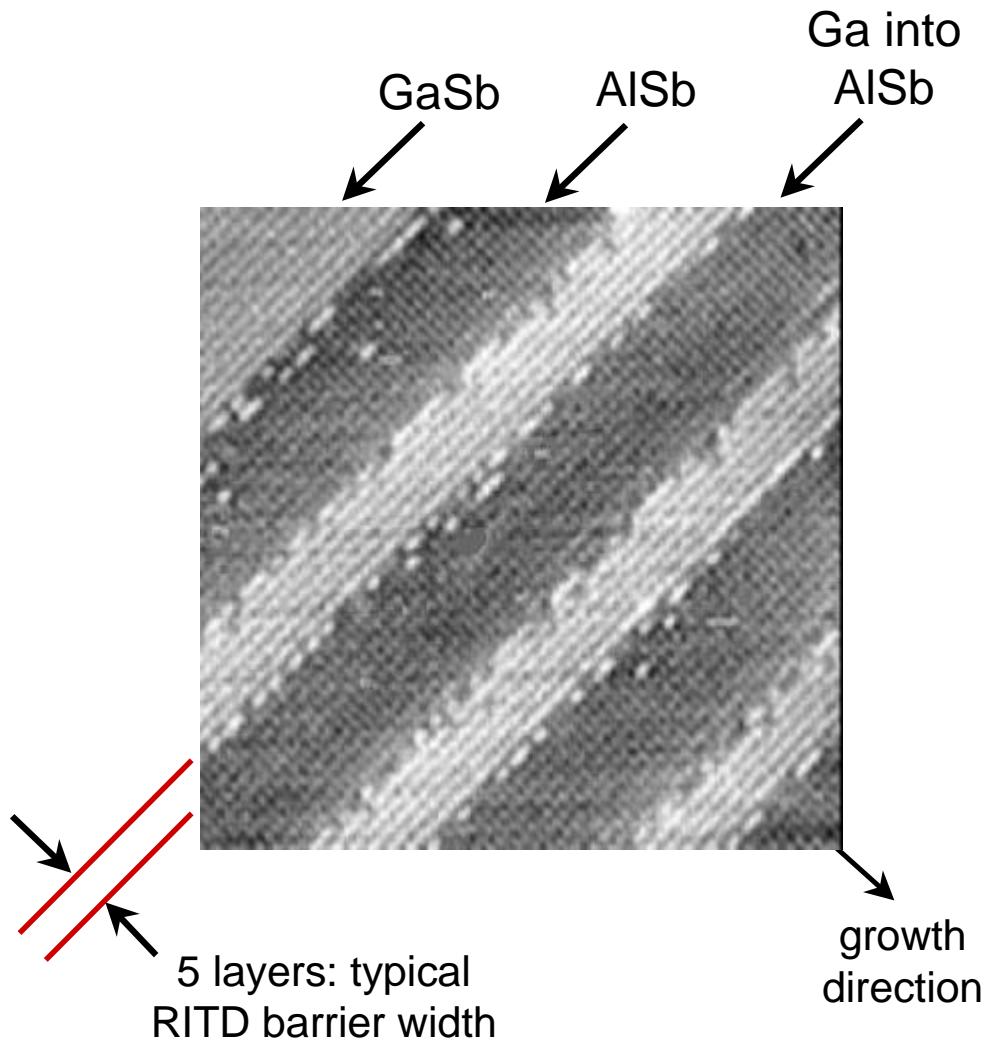
Influence of Ga segregation on Peak current



Segregation reduces top barrier gap
to increase reverse bias current.

Roughness will also contribute (with opposite temperature dependence), complicating interpretation.

Ga segregation into AlSb



Conclusions

- Higher peak currents result from
 1. Interface roughness at low growth temperature
 2. Gallium segregation at higher growth temperature
- Sudden reconstruction changes can lead to island formation with antimonides
- Barrier alloying permits higher peak currents with possible reduced sensitivity to interface flaws